

1Msps 8-Bit Cyclic ADC IP

Marketing Brief

Epoch Microelectronics, Inc.
Valhalla, NY

8-Bit 1Msps Cyclic ADC: Features/Deliverables

Features:

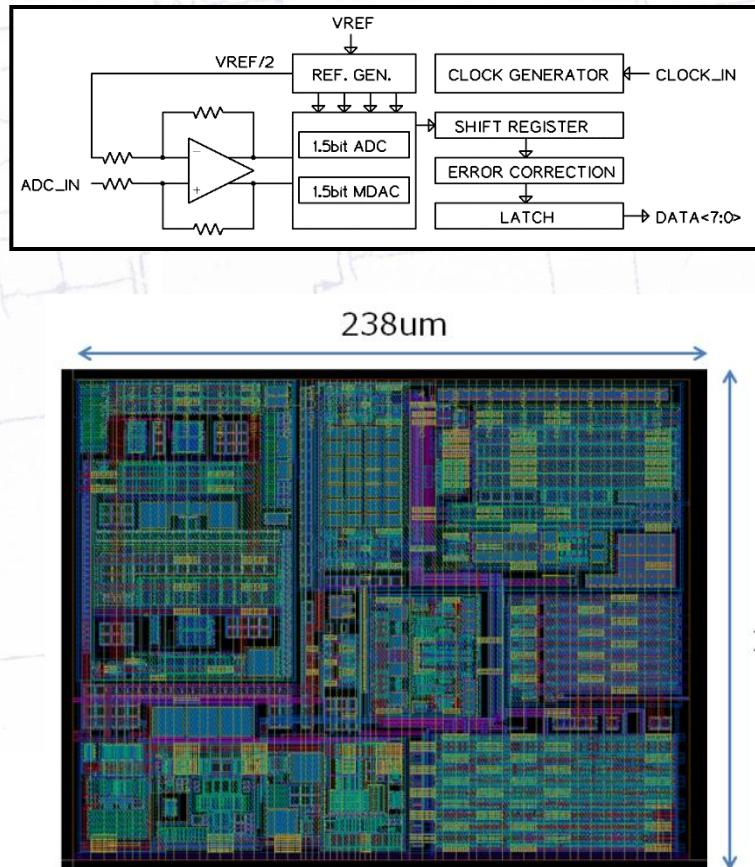
- Single to differential ADC driver amplifier
- Fully differential Cyclic ADC with bit controllable unsigned or signed output
- 1.5bit MDAC/ADC architecture with error correction.
- Internal reference buffers and generator from single 1.45V voltage reference
- Small Die Area

Deliverables:

- White Box:
 - Cadence library including schematics, layout, and test benches
 - GDS2, CDL netlist, DRC/LVS/ERC reports
 - Verilog and .LIB files
 - Evaluation report
- Black Box:
 - GDS2, CDL netlist, DRC/LVS/ERC reports
 - Verilog and .LIB files
 - Encrypted SPICE netlist
 - Evaluation report

8-Bit 1Msps Cyclic ADC

Technology	Global Foundries 40nm CMOS
Process Options	6L1x_1T6x_1T18x_LB
Analog Supply Voltage	1.8V
Digital Supply Voltage	1.1V
Sampling Rate	1Msps
Input Voltage Swing	$1.45V_{pp}$
ENOB	7.7bit
SNDR	47.9dB
Active Chip Area	0.044mm ²
Power (Analog)	1.6mW
Power (Digital)	0.003mW
Status	GDS2 ready (evaluation completed)

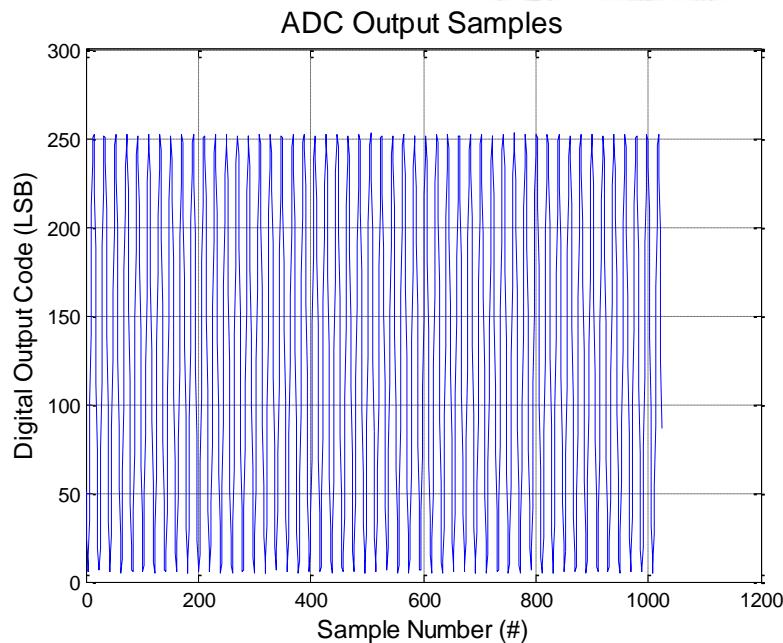


Measured Summary (TT, SS, FF Samples)

Measured Item	TT Sample	SS Sample	FF Sample
HD2	-69.0	-65.8	-66.6
HD3	-59.1	-61.4	-60.9
THD	-58.3	-58.4	-58.4
SFDR	59.1	61.4	60.9
SNR	48.3	48.2	48.4
SNDR	47.9	47.8	48.0
ENOB	7.7	7.7	7.7
DNL	-0.17 / +0.13	-0.2 / +0.12	-0.17 / +0.12
INL	-0.3 / +0.2	-0.3 / +0.17	-0.3 / +0.18

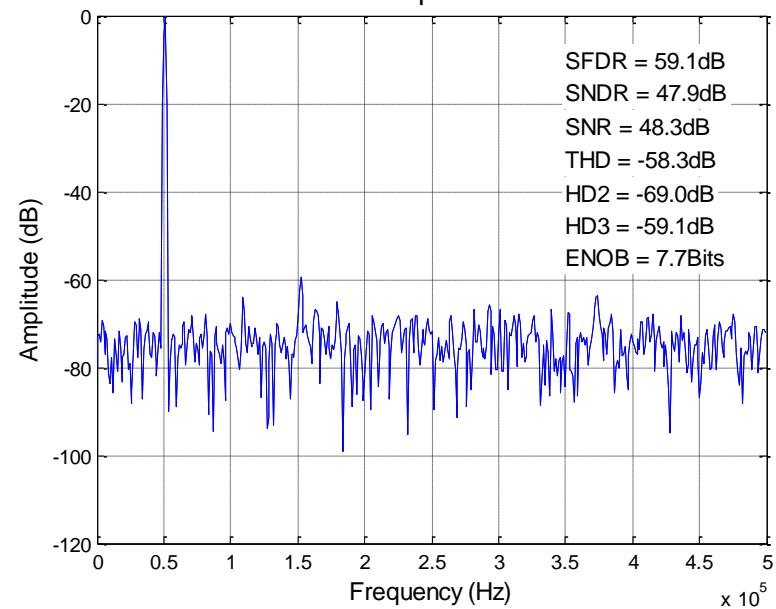
Measured Spectrum: TT Sample

Output Samples



MaximFFT [blackman,1024pts]
Signal Span=5bins, Harmonic Span=2bins

FFT Spectrum

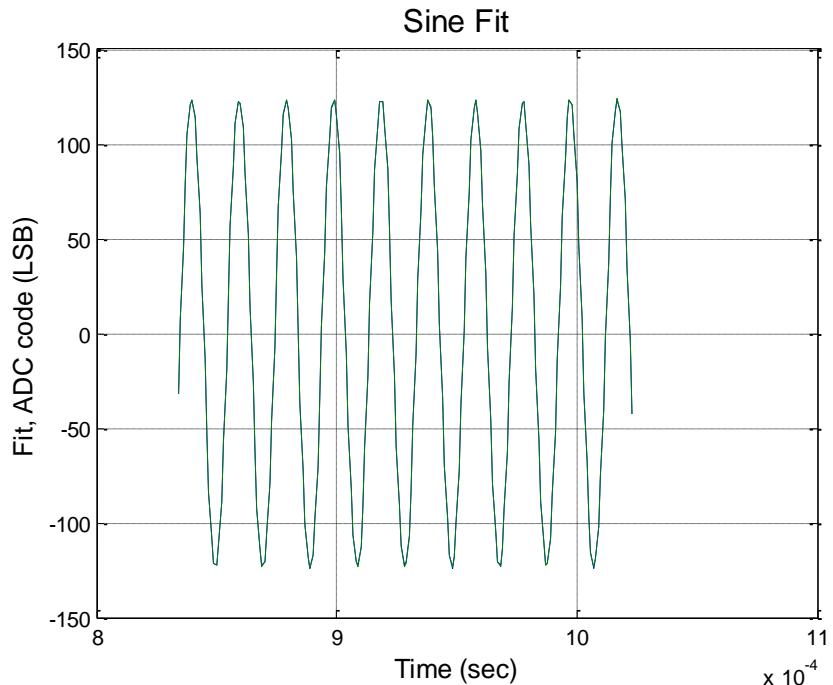


ENOB = 7.7 (blackman window)

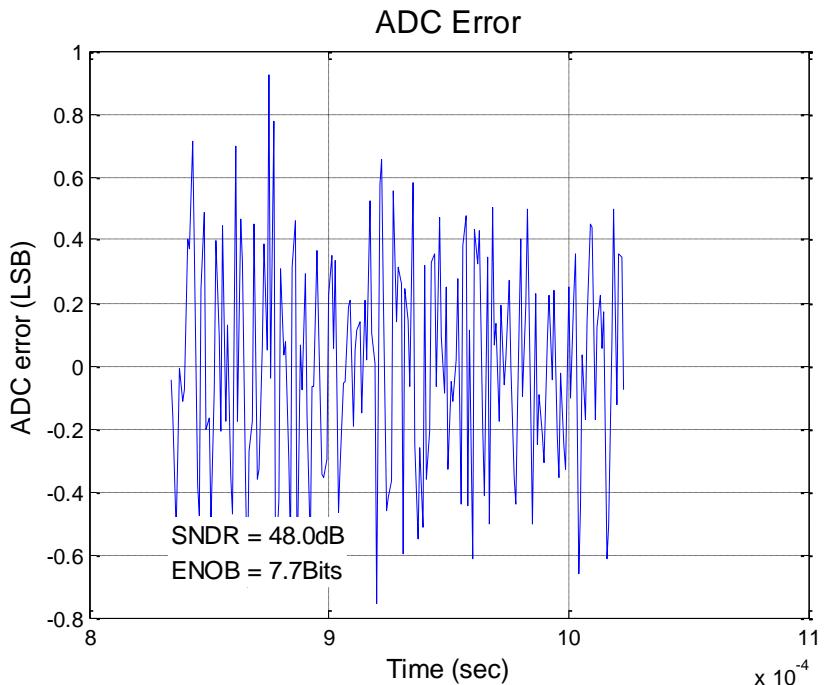
Measurement Conditions: Vin = 1.45Vpp, Fs = 1Msps, Temp = Room

Measured Sine Fit: TT Sample

Sine Fit & ADC Output



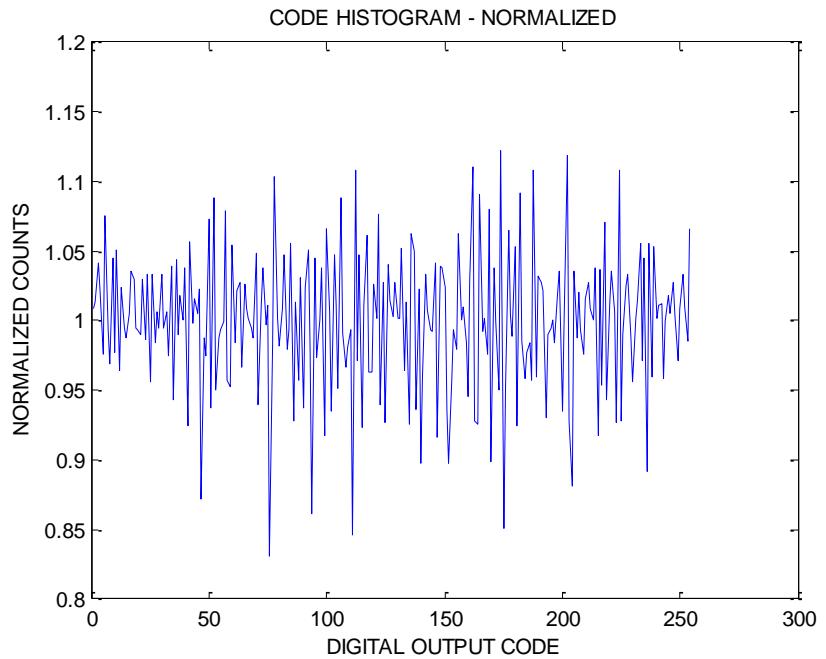
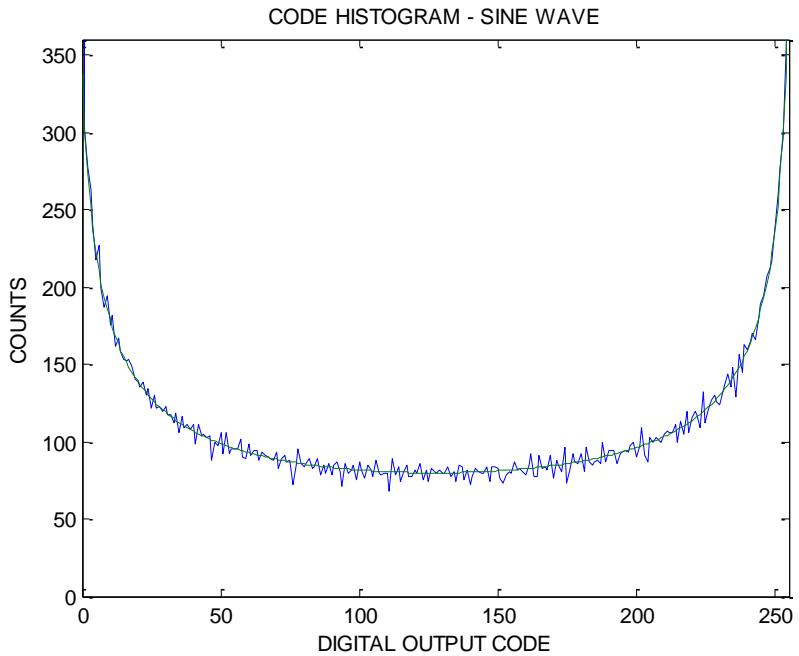
ADC Error



ENOB = 7.7 (10 sine cycles)

Measurement Conditions: Vin = 1.45Vpp, Fs = 1Msps, Temp = Room

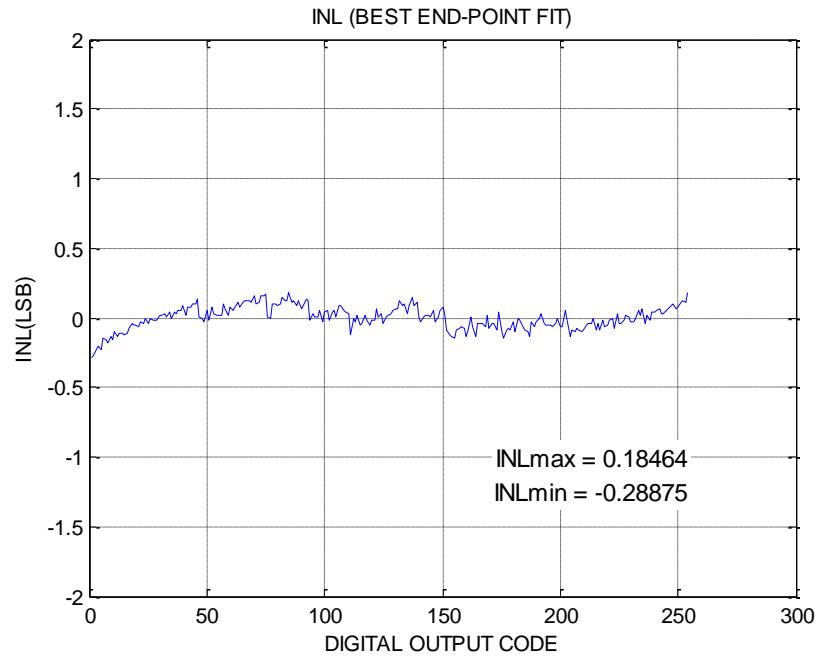
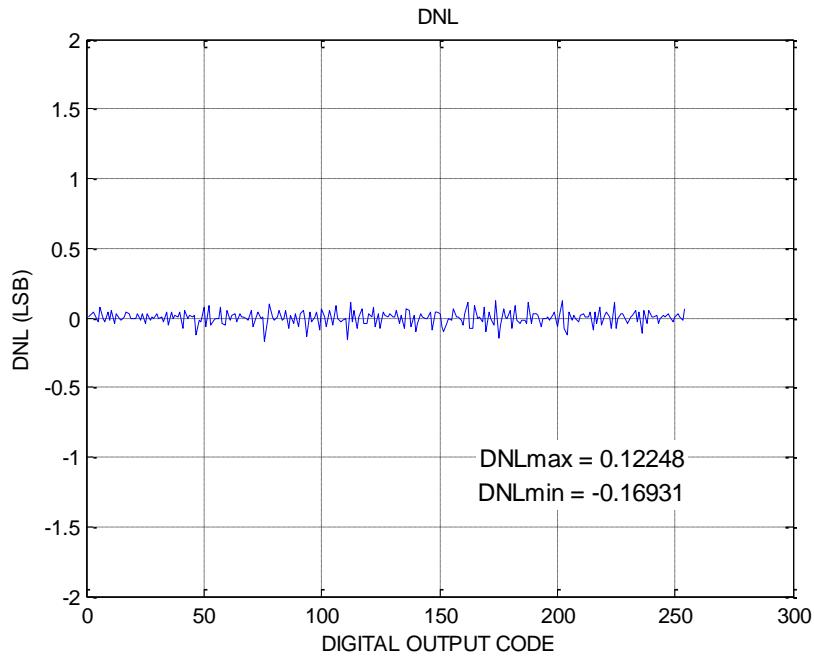
Measured Histogram: TT Sample



Histogram shows all codes hit (no missing code)

Measurement Conditions: Vin = 1.55Vpp, Fs = 1Msps, Temp = Room

Measured DNL/INL: TT Sample



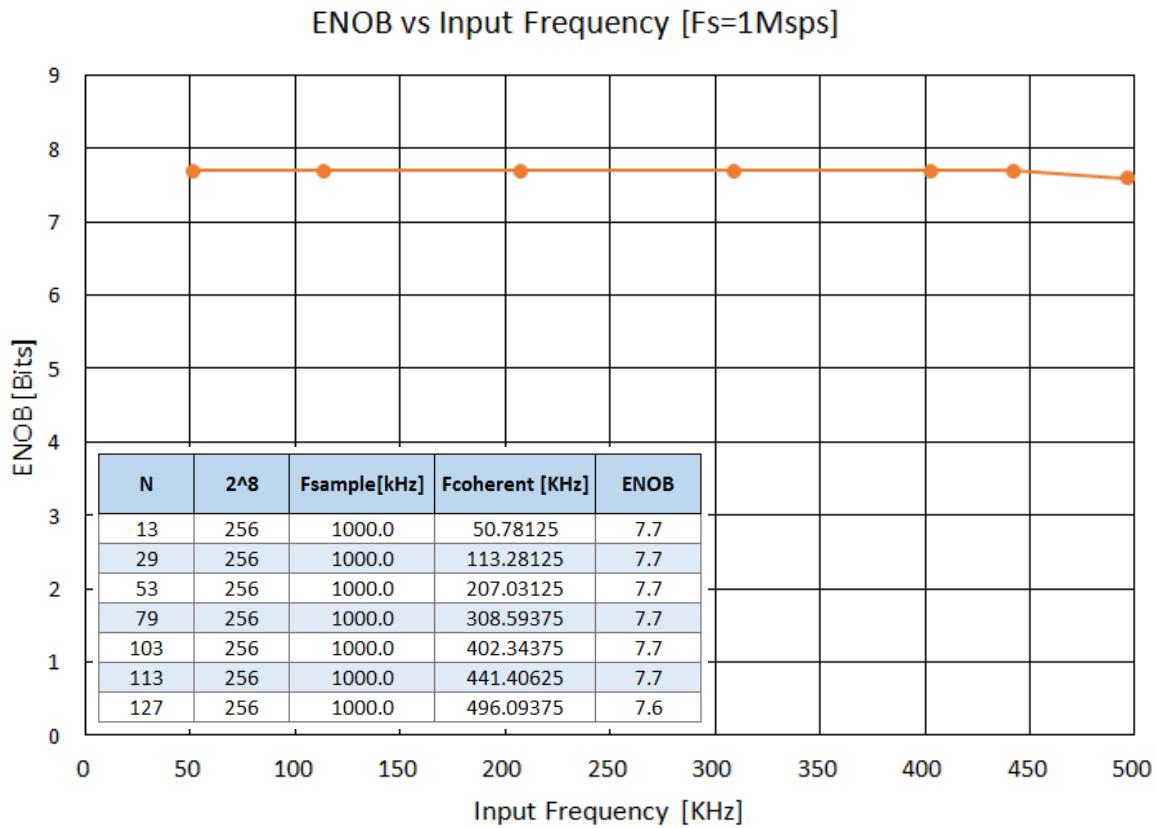
$$\text{DNL} = -0.17 / +0.13 \text{ LSB}$$

$$\text{INL} = -0.3 / +0.2 \text{ LSB}$$

$$\text{SFDR} = 20\log(2^N/\text{INL}) = 58.6\text{dB} \text{ (consistent with measured SFDR)}$$

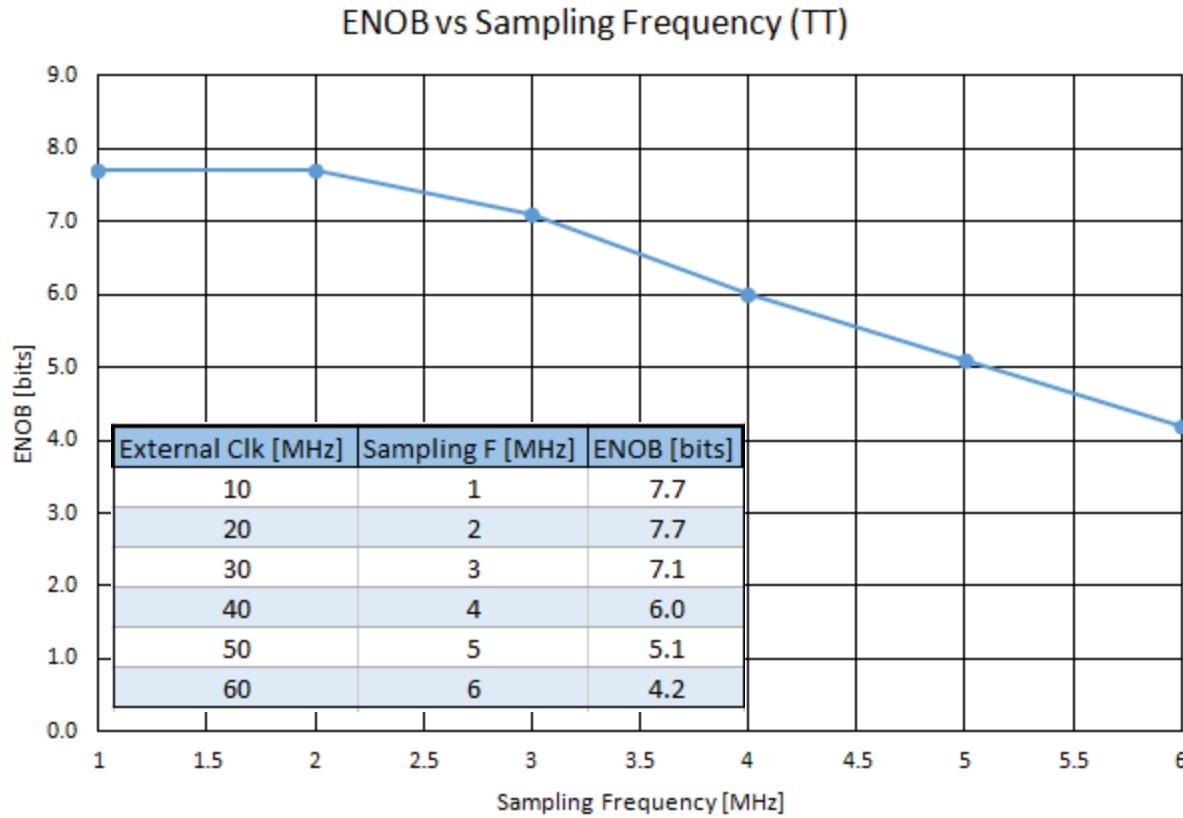
Measurement Conditions: Vin = 1.55Vpp, Fs = 1Msps, Temp = Room

ENOB vs Input Frequency: TT Sample



No Meaningful ENOB Degradation Up To Nyquist ($F_{in} = F_{sample}/2$)

ENOB vs Sampling Frequency: TT Sample



No ENOB Degradation @ 2Msps

Measurement Conditions: Vin = 1.45Vpp, Fs = Sweep, Temp = Room

ENOB vs Supply & Temperature: TT

N	Fcoherent [KHz]
13	50.78125
29	113.28125
53	207.03125
79	308.59375
103	402.34375
113	441.40625
127	496.09375

Input Frequency: $(N/256) * 1\text{Msps}$

Measurement Item	Temperature	Vdd11_digital	Vdd18_analog	Units	TT-sample						
					N = 13	N = 29	N = 53	N = 79	N = 103	N = 113	N = 127
ENOB vs Fin <i>Fsample = 1MHz</i> <i>Vin = 1.45Vpp</i> <i>Fin = sweep</i>	25C	0.99V	1.62V	bit	7.7	7.7	7.7	7.6	7.6	7.6	7.7
		1.1V	1.8V		7.7	7.7	7.7	7.7	7.7	7.7	7.6
		1.2V	2.0V		7.7	7.7	7.6	7.6	7.6	7.7	7.6
	-40C	0.99V	1.62V		7.7	7.7	7.7	7.6	7.6	7.6	7.6
		1.1V	1.8V		7.7	7.7	7.6	7.6	7.6	7.6	7.6
		1.2V	2.0V		7.7	7.7	7.7	7.6	7.7	7.6	7.6
	+85C	0.99V	1.62V		7.7	7.7	7.7	7.6	7.7	7.6	7.6
		1.1V	1.8V		7.7	7.7	7.6	7.6	7.6	7.6	7.7
		1.2V	2.0V		7.6	7.7	7.6	7.6	7.6	7.6	7.6
	+105C	0.99V	1.62V		7.7	7.7	7.6	7.7	7.6	7.6	7.6
		1.1V	1.8V		7.7	7.7	7.6	7.6	7.6	7.6	7.6
		1.2V	2.0V		7.7	7.7	7.6	7.6	7.6	7.6	7.6
	+125C	0.99V	1.62V		7.6	7.6	7.6	7.6	7.6	7.6	7.6
		1.1V	1.8V		7.7	7.6	7.6	7.6	7.6	7.6	7.5
		1.2V	2.0V		7.7	7.7	7.6	7.6	7.6	7.6	7.6

TT Sample measurements over supply & temperature show no meaningful ENOB degradation for input frequencies up to $F_{\text{sample}}/2$

ENOB vs Supply & Temperature: FF

N	Fcoherent [KHz]
13	50.78125
29	113.28125
53	207.03125
79	308.59375
103	402.34375
113	441.40625
127	496.09375

Input Frequency: $(N/256)^* 1\text{Msps}$

Measurement Item	Temperature	Vdd11_digital	Vdd18_analog	Units	FF-sample						
					N = 13	N = 29	N = 53	N = 79	N = 103	N = 113	N = 127
ENOB vs Fin <i>Fsample = 1MHz</i> <i>Vin = 1.45Vpp</i> <i>Fin = sweep</i>	25C	0.99V	1.62V	bit	7.7	7.7	7.7	7.7	7.6	7.6	7.6
		1.1V	1.8V		7.7	7.7	7.7	7.6	7.7	7.6	7.7
		1.2V	2.0V		7.7	7.7	7.7	7.7	7.7	7.7	7.7
	-40C	0.99V	1.62V		7.8	7.7	7.7	7.6	7.6	7.6	7.6
		1.1V	1.8V		7.7	7.7	7.7	7.7	7.7	7.7	7.7
		1.2V	2.0V		7.7	7.7	7.7	7.7	7.7	7.7	7.6
	+85C	0.99V	1.62V		7.6	7.7	7.6	7.7	7.6	7.7	7.6
		1.1V	1.8V		7.7	7.6	7.6	7.6	7.6	7.6	7.6
		1.2V	2.0V		7.7	7.7	7.6	7.6	7.6	7.7	7.7
	+105C	0.99V	1.62V		7.6	7.7	7.6	7.6	7.6	7.7	7.6
		1.1V	1.8V		7.7	7.7	7.7	7.7	7.6	7.6	7.6
		1.2V	2.0V		7.7	7.7	7.6	7.6	7.6	7.6	7.6
	+125C	0.99V	1.62V		7.7	7.7	7.7	7.6	7.6	7.6	7.6
		1.1V	1.8V		7.6	7.7	7.6	7.6	7.6	7.6	7.5
		1.2V	2.0V		7.6	7.7	7.6	7.5	7.6	7.6	7.5

FF Sample measurements over supply & temperature show no meaningful ENOB degradation for input frequencies up to $F_{\text{sample}}/2$

ENOB vs Supply & Temperature: SS

N	Fcoherent [KHz]
13	50.78125
29	113.28125
53	207.03125
79	308.59375
103	402.34375
113	441.40625
127	496.09375

Input Frequency: $(N/256) * 1 \text{ Msps}$

Measurement Item	Temperature	Vdd11_digital	Vdd18_analog	Units	SS-sample						
					N = 13	N = 29	N = 53	N = 79	N = 103	N = 113	N = 127
ENOB vs Fin $f_{sample} = 1 \text{ MHz}$ $Vin = 1.45 \text{ Vpp}$ $Fin = \text{sweep}$	25C	0.99V	1.62V	bit	7.8	7.7	7.7	7.6	7.7	7.6	7.6
		1.1V	1.8V		7.7	7.7	7.6	7.6	7.6	7.7	7.6
		1.2V	2.0V		7.7	7.7	7.7	7.6	7.6	7.6	7.7
	-40C	0.99V	1.62V		7.7	7.7	7.7	7.6	7.6	7.7	7.6
		1.1V	1.8V		7.8	7.7	7.7	7.6	7.6	7.6	7.7
		1.2V	2.0V		7.8	7.7	7.7	7.7	7.6	7.6	7.6
	+85C	0.99V	1.62V		7.8	7.7	7.7	7.7	7.6	7.6	7.6
		1.1V	1.8V		7.7	7.7	7.7	7.7	7.6	7.7	7.6
		1.2V	2.0V		7.8	7.7	7.7	7.7	7.6	7.6	7.6
	+105C	0.99V	1.62V		7.7	7.7	7.7	7.6	7.7	7.6	7.6
		1.1V	1.8V		7.7	7.7	7.7	7.7	7.7	7.6	7.6
		1.2V	2.0V		7.7	7.7	7.7	7.6	7.6	7.7	7.7
	+125C	0.99V	1.62V		7.7	7.7	7.6	7.5	7.6	7.6	7.6
		1.1V	1.8V		7.7	7.7	7.6	7.7	7.6	7.6	7.6
		1.2V	2.0V		7.7	7.6	7.7	7.7	7.6	7.6	7.6
	+150C	0.99V	1.62V		7.6	7.5	7.5	7.5	7.5	7.6	7.5

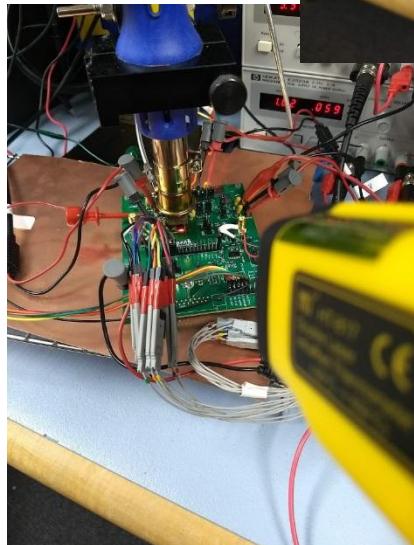
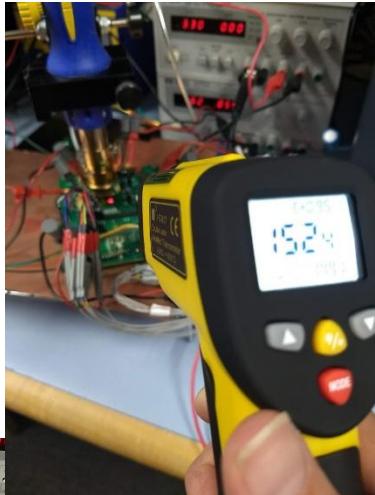
SS Sample measurements over supply & temperature show no meaningful ENOB degradation for input frequencies up to $f_{sample}/2$

Note: -40C to 125C evaluation done in temperature chamber. 150C measurement done with heating up only the chip.

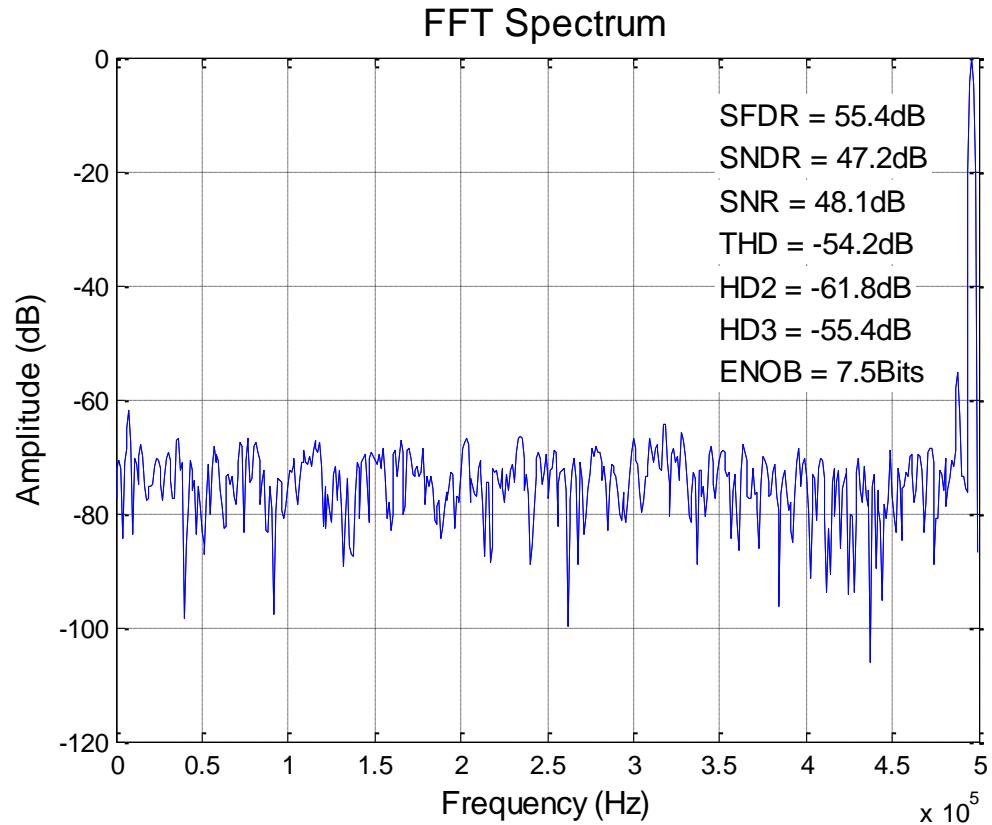
Evaluation @ 150C: Worst Case

SS/150C/0.99V/1.62V, Fin= 496.09375kHz

- (1) Chip heated up with Hakko hot air flow.
- (2) Chip temperature measured with dual laser infrared thermometer



MaximFFT [blackman,1024pts]
Signal Span=5bins, Harmonic Span=2bins



Thank you!



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